

## **Experimental Workshop Department** Integrity and Technical Engineering Division



# FAILURE ANALYSIS OF ENGINEERING STRUCTURES

Destruction of a heating element

#### Value for customers

- Failure analysis performed on damaged components and structures allows determination of the root cause of the defect
- Knowing the principal cause of the failure enables to define and implement the appropriate corrective measures to prevent the defect from reappearing
- This proactive approach saves the operational costs, improves the safety and availability of the engineering systems

#### **Applications**

 Analysis of the root causes of damage is applicable to various systems, structures and components in both nuclear plants and other large engineering structures

#### What we offer

- Evaluation of damaged engineering structures failed during operation
- Failure analysis using multidisciplinary approach (optical microscopy, scanning electron microscopy, X-ray microanalysis, microhardness measurement, evaluation the role of environment etc.)

#### **Contact details**

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- Determination of the root cause and proposal of the corrective measures preventing risk of repetitive failures
- Evaluation of non-radioactive as well as radioactive material
- Testing laboratory certified by the Czech national authority ČIA
- A quality assurance system according to ČSN EN ISO/IEC 17025 in accordance with ISO 9001 standards

### **Our references**

- Failure analysis of different engineering structures at Dukovany and Temelin nuclear plants
- Fossil power plants (Opatovice plant)
- Chemical industry (Czech Refinery)



Microbiologically induced corrosion the piping from the austenitic stainless steel – SEM micrograph (left) and the defect on the outer surface (right)